

## OBITUARY

It is with great sadness that we inform you that Sergey Kharkovsky, one of the journal's Associate Editors, passed away on September 6, 2017.

Sergey had served as an Associate Editor since 2008, and was Associate Editor-in-Chief in 2014. His competence and expertise in the field of microwave measurement methods and instruments and in the field of non-destructive testing were simply indispensable to the journal. He was not only extremely competent, but his diligence was also outstanding and his recommendations were always aimed at helping the authors improve their work. Even when the recommendation was a Reject, he paid great attention to explaining the reasons in details, so that the authors could find an encouragement to reconsider their work, revise and eventually resubmit it. If this journal has improved its metrics and its overall quality, it is also thanks to the time and energy that people like Sergey have devoted to it.

Those of us who worked with him are not missing only a great colleague. We are missing a smiling friend and a person of the highest character, who was always there when we needed a frank advice or an exchange of ideas. His sudden and totally unexpected death has left a void in the TIM family.

Rest in peace Sergey. We will miss you!

Shervin Shirmohammadi,  
EiC

Alessandro Ferrero  
Associate EiC

